



APT30M85SVR

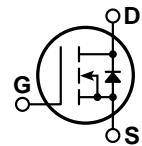
300V 40A 0.085Ω

POWER MOS V

Power MOS V is a new generation of high voltage N-Channel enhancement mode power MOSFETs. This new technology minimizes the JFET effect, increases packing density and reduces the on-resistance. Power MOS V also achieves faster switching speeds through optimized gate layout.



- Faster Switching
- Lower Leakage
- 100% Avalanche Tested
- Surface Mount D³PAK Package



MAXIMUM RATINGS

All Ratings: $T_C = 25^\circ\text{C}$ unless otherwise specified.

Symbol	Parameter	APT30M85SVR	UNIT
V_{DSS}	Drain-Source Voltage	300	Volts
I_D	Continuous Drain Current @ $T_C = 25^\circ\text{C}$	40	Amps
I_{DM}	Pulsed Drain Current ^①	160	
V_{GS}	Gate-Source Voltage Continuous	± 20	Volts
V_{GSM}	Gate-Source Voltage Transient	± 30	
P_D	Total Power Dissipation @ $T_C = 25^\circ\text{C}$	300	Watts
	Linear Derating Factor	2.4	W/ $^\circ\text{C}$
T_J, T_{STG}	Operating and Storage Junction Temperature Range	-55 to 150	$^\circ\text{C}$
T_L	Lead Temperature: 0.063" from Case for 10 Sec.	300	
I_{AR}	Avalanche Current ^① (Repetitive and Non-Repetitive)	40	Amps
E_{AR}	Repetitive Avalanche Energy ^①	30	
E_{AS}	Single Pulse Avalanche Energy ^④	1300	mJ

STATIC ELECTRICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
BV_{DSS}	Drain-Source Breakdown Voltage ($V_{GS} = 0\text{V}$, $I_D = 250\mu\text{A}$)	300			Volts
$I_{D(on)}$	On State Drain Current ^② ($V_{DS} > I_{D(on)} \times R_{DS(on)}$ Max, $V_{GS} = 10\text{V}$)	40			Amps
$R_{DS(on)}$	Drain-Source On-State Resistance ^② ($V_{GS} = 10\text{V}$, $0.5 I_{D(\text{Cont.})}$)			0.085	Ohms
I_{DSS}	Zero Gate Voltage Drain Current ($V_{DS} = V_{DSS}$, $V_{GS} = 0\text{V}$)			25	μA
	Zero Gate Voltage Drain Current ($V_{DS} = 0.8 V_{DSS}$, $V_{GS} = 0\text{V}$, $T_C = 125^\circ\text{C}$)			250	
I_{GSS}	Gate-Source Leakage Current ($V_{GS} = \pm 20\text{V}$, $V_{DS} = 0\text{V}$)			± 100	nA
$V_{GS(th)}$	Gate Threshold Voltage ($V_{DS} = V_{GS}$, $I_D = 1.0\text{mA}$)	2	4		Volts

CAUTION: These Devices are Sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

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DYNAMIC CHARACTERISTICS

APT30M85SVR

Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT
C_{iss}	Input Capacitance	$V_{GS} = 0V$ $V_{DS} = 25V$ $f = 1\text{ MHz}$		3970		pF
C_{oss}	Output Capacitance			750		
C_{rss}	Reverse Transfer Capacitance			230		
Q_g	Total Gate Charge ③	$V_{GS} = 10V$ $V_{DD} = 0.5 V_{DSS}$ $I_D = I_{D[\text{Cont.}]} @ 25^\circ\text{C}$		145		nC
Q_{gs}	Gate-Source Charge			25		
Q_{gd}	Gate-Drain ("Miller") Charge			59		
$t_{d(on)}$	Turn-on Delay Time	$V_{GS} = 15V$ $V_{DD} = 0.5 V_{DSS}$ $I_D = I_{D[\text{Cont.}]} @ 25^\circ\text{C}$ $R_G = 1.6\Omega$		12		ns
t_r	Rise Time			10		
$t_{d(off)}$	Turn-off Delay Time			43		
t_f	Fall Time			7		

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
I_S	Continuous Source Current (Body Diode)			40	Amps
I_{SM}	Pulsed Source Current ① (Body Diode)			160	
V_{SD}	Diode Forward Voltage ② ($V_{GS} = 0V$, $I_S = -I_{D[\text{Cont.}]}$)			1.3	Volts
t_{rr}	Reverse Recovery Time ($I_S = -I_{D[\text{Cont.}]}$, $dI_S/dt = 100A/\mu\text{s}$)		390		ns
Q_{rr}	Reverse Recovery Charge ($I_S = -I_{D[\text{Cont.}]}$, $dI_S/dt = 100A/\mu\text{s}$)		6		μC

THERMAL CHARACTERISTICS

Symbol	Characteristic	MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Junction to Case			0.42	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Junction to Ambient			40	

① Repetitive Rating: Pulse width limited by maximum junction temperature.

③ See MIL-STD-750 Method 3471

④ Starting $T_j = +25^\circ\text{C}$, $L = 1.63\text{mH}$, $R_G = 25\Omega$, Peak $I_L = 40\text{A}$

② Pulse Test: Pulse width < 380 μs , Duty Cycle < 2%

APT Reserves the right to change, without notice, the specifications and information contained herein.

D³PAK Package Outline

